Supplementary Materials

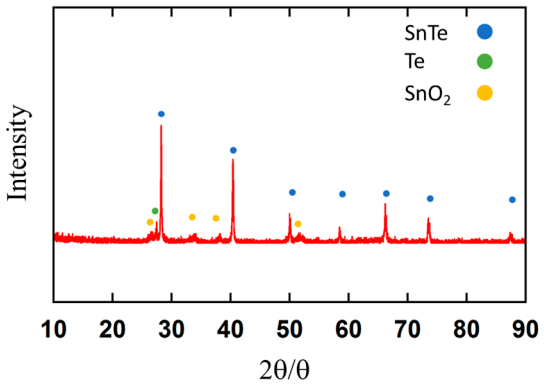

Figure S1. XRD patterns of the as prepared precursors

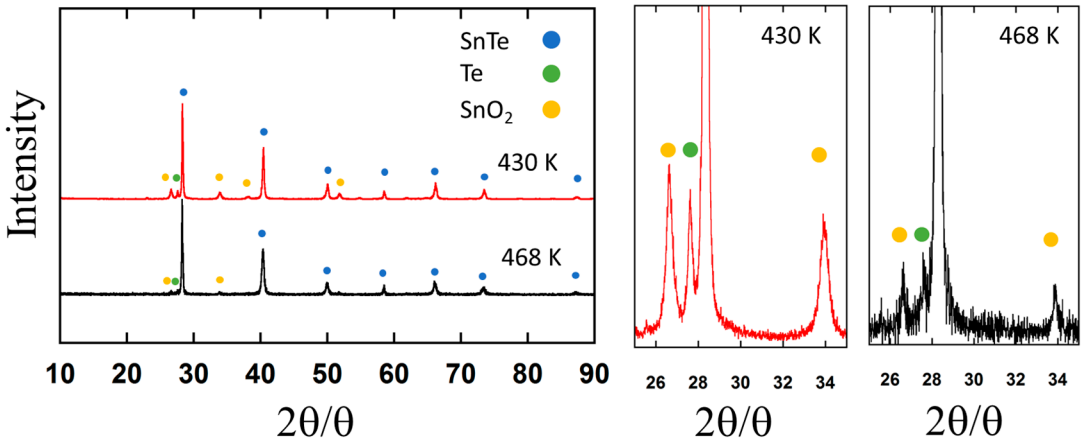

Figure S2. XRD patterns of the sintered sample prepared from SnTe nanocrystals annealed at 430 K (red) and 468 K (black)

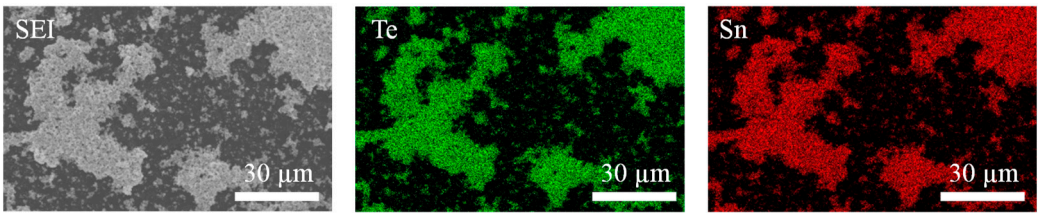

Figure S3. SEM image and EDS mapping data for the annealed SnTe nanocrystals (precursor).

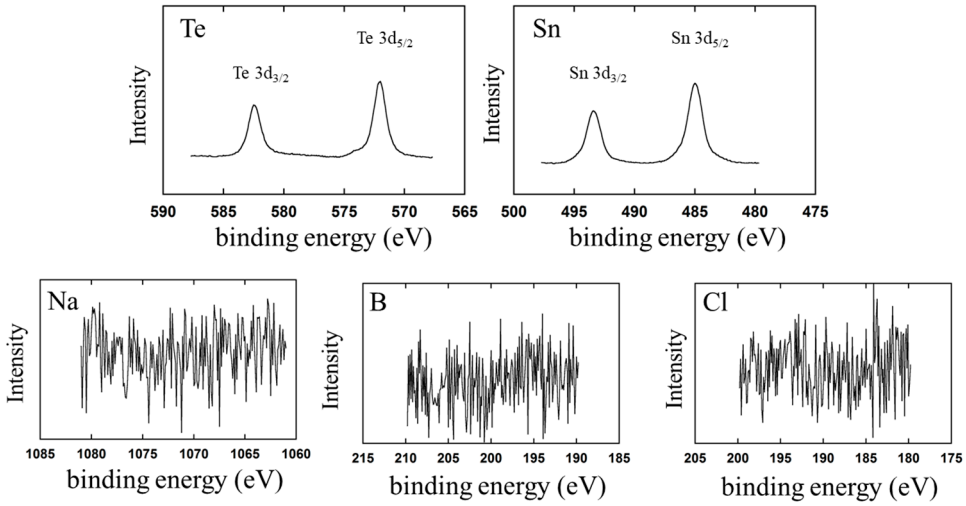

Figure S4. XPS scans for Te 3d, Sn 3d, Na 1s, B 1s, and Cl 2p from the sintered SnTe sample: The sintered sample was etched with Ar for 60 s.

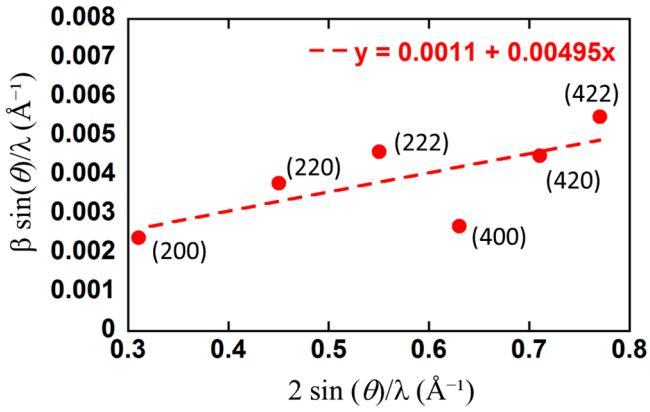

Figure S5. Williamson–Hall strain analysis of the sintered SnTe sample. Plotting $\beta\sin(\theta)/\lambda$ versus $2\varepsilon\sin(\theta)/\lambda$. The intercept value indicates the average crystallite size, and half value of the slope indicates the internal strain rate.